

FORM PTO-1449 (modified) To: U.S. Department of Commerce (PW FORM PAT-1449) Patent and Trademark Office			Atty. Dkt. No.	M#	Client Ref.:
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**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Date: January 5, 2010      Page **1** of **1**      Examiner: MOORE, W.      Group Art Unit: 2826

**U.S. PATENT DOCUMENTS**

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AR	5,770,861	06-23-1998	Hirose et al.			
BR						
CR						
DR						
ER						
FR						
GR						
HR						
IR						
JR						
KR						
LR						
MR						
NR						

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
					Enclosed	No	Enclose	No
OR								
PR								
QR								
RR								
SR								
TR								

**OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)**

UR	Inkon B J et al.: "Subsurface nanoindentation deformation of Cu-Al multilayers mapped in 3D by focused ion beam microscopy," Journal of Microscopy, vol. 201, pt. 2, February 2001, pp. 256-269	X
VR	Dunn D N et al.: "Reconstruction of three-dimensional chemistry and geometry using focused ion beam microscopy," Applied Science Letters, vol. 75, number 21, November 22, 1999, pages 3414-3416	X
WR	Sakamoto T. et al.: "Development of an ion and electron dual focused beam apparatus for three-dimensional microanalysis," Japanese Journal of Applied Physics, vol. 37, no. 4A, April 1998, pages 2051-2056	X
XR	Supplementary European Search Report for European Application Number EP 03 75 6661 dated December 17, 2009	X

Examiner \_\_\_\_\_ Date Considered: \_\_\_\_\_

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.